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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/071,174	REED ET AL.	
Examiner	Art Unit	
Jon Eric Angell	1635	

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Class	Subclass	Date	Examiner
536	23.1, 24.33	6/8/2005	JEA
536	24.3+	6/8/2005	JEA
435	320.1 325	6/8/2005	JEA
435	252.3	6/8/2005	JEA
Upda	ited	3-2-20%	DEL
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
STN EAST Inventor Name searched STIC SEQ search: SEQs 1, 2, 37 including alignment of 1 and 37 Reviewed and Updated	6/8/2005	JEA	
Updated	3-2-2006	DEA	